previous engineering

sample codes: IPP02CN08N

٧

 $\mathsf{m}\Omega$

Α

80

2.8

100

Product Summary

 $V_{\rm DS}$

 I_D

 $R_{\,\mathrm{DS(on),max}}$



OptiMOS[®]3 Power-Transistor

Features

- N-channel, normal level
- Excellent gate charge $x R_{DS(on)}$ product (FOM)
- Very low on-resistance R_{DS(on)}
- 175 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC¹⁾ for target application
- Ideal for high-frequency switching and synchronous rectification

Туре	IPP028N08N3 G	IPI028N08N3 G
	123	123
Package	PG-TO220-3	PG-TO262-3
Marking	028N08N	028N08N

drain pin 2

Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	T _C =25 °C ²⁾	100	Α
		T _C =100 °C	100	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	400	
Avalanche energy, single pulse	E _{AS}	$I_{\rm D}$ =100 A, $R_{\rm GS}$ =25 Ω	1430	mJ
Gate source voltage	V_{GS}		±20	V
Power dissipation	P tot	T _C =25 °C	300	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

IPP028N08N3 G IPI028N08N3 G

Parameter	Symbol	Conditions	Values		Unit		
			min.	typ.	max.		
Thermal characteristics							
Thermal resistance, junction - case	$R_{ m thJC}$		-	-	0.5	K/W	
Thermal resistance,	$R_{ m thJA}$	minimal footprint	-	-	62		
junction - ambient		6 cm ² cooling area ³⁾	-	-	40		

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =1 mA	80	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}$ = $V_{\rm GS}$, $I_{\rm D}$ =270 μ A	2	2.8	3.5	
Zero gate voltage drain current	I _{DSS}	V _{DS} =80 V, V _{GS} =0 V, T _j =25 °C	1	0.1	1	μΑ
		V _{DS} =80 V, V _{GS} =0 V, T _j =125 °C	-	10	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	1	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =100 A	-	2.4	2.8	mΩ
		V _{GS} =6 V, I _D =50 A	-	2.8	4.2	
Gate resistance	R _G		-	2.7	-	Ω
Transconductance	g _{fs}	V _{DS} >2 I _D R _{DS(on)max} , I _D =100 A	94	187	-	s

¹⁾J-STD20 and JESD22

²⁾ See figure 3

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



IPP028N08N3 G IPI028N08N3 G

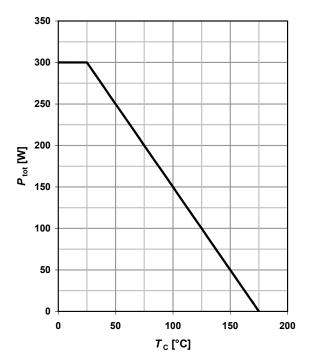
Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss		-	10700	14200	pF
Output capacitance	C oss	V _{GS} =0 V, V _{DS} =40 V, f=1 MHz	-	2890	3840	
Reverse transfer capacitance	C _{rss}]	-	100	150	
Turn-on delay time	t _{d(on)}		-	28	-	ns
Rise time	t _r	V _{DD} =40 V, V _{GS} =10 V,	-	73	-	
Turn-off delay time	t _{d(off)}	$I_{\rm D}$ =100 A, $R_{\rm G}$ =1.6 Ω	-	86	-	
Fall time	t _f]	-	33	-	
Gate Charge Characteristics ⁴⁾				T		
Gate to source charge	Q _{gs}		-	50	67	nC
Gate to drain charge	Q_{gd}		-	30	45	
Switching charge	Q _{sw}	V _{DD} =40 V, I _D =100 A, V _{GS} =0 to 10 V	-	50	72	
Gate charge total	Q _g		-	155	206	
Gate plateau voltage	V _{plateau}		-	4.7	ı	٧
Output charge	Q oss	V _{DD} =40 V, V _{GS} =0 V	-	210	279	nC
Reverse Diode						
Diode continous forward current	Is	- 7 _С =25 °С	-	-	100	Α
Diode pulse current	I _{S,pulse}	7 _C -23 C	-	-	400	1
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =100 A, T _j =25 °C	-	1.0	1.2	V
Reverse recovery time	t _{rr}	V _R =40 V, I _F =I _S ,	-	113	-	ns
Reverse recovery charge	Q _{rr}	d: /dt=100 A/vo		317	_	nC

⁴⁾ See figure 16 for gate charge parameter definition



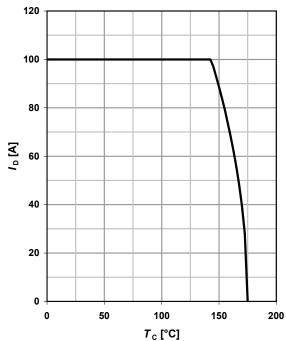
1 Power dissipation

P_{tot} =f(T_{C})



2 Drain current

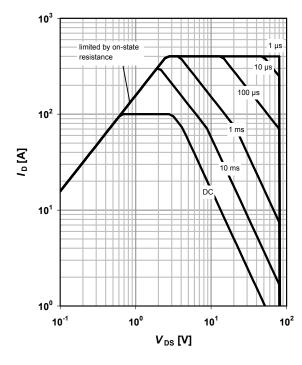
$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$



3 Safe operating area

$$I_D = f(V_{DS}); T_C = 25 \,^{\circ}C; D = 0$$

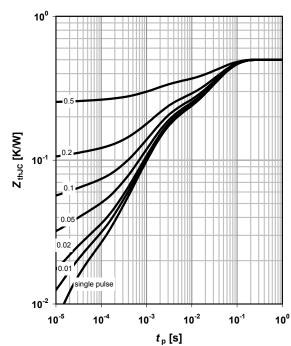
parameter: $t_{\rm p}$



4 Max. transient thermal impedance

$$Z_{thJC}$$
=f(t_p)

parameter: $D = t_p/T$

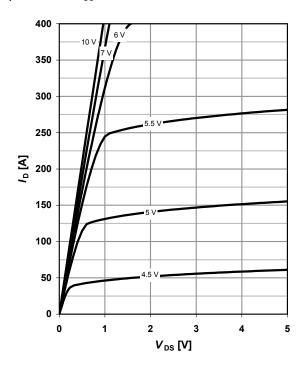




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C$

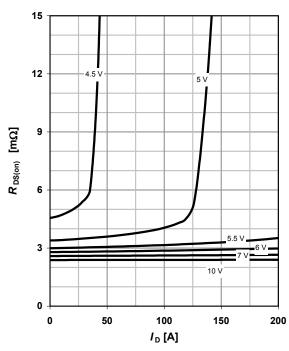
parameter: $V_{\rm GS}$



6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f(I_D); T_j =25 °C

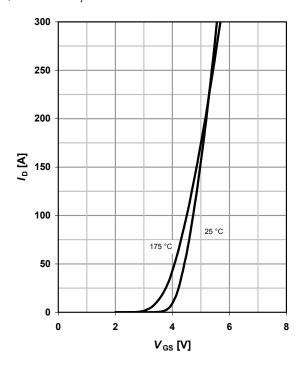
parameter: $V_{\rm GS}$



7 Typ. transfer characteristics

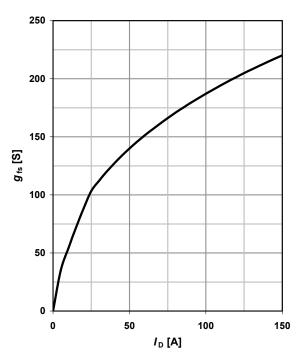
 $I_{\rm D}$ =f($V_{\rm GS}$); $|V_{\rm DS}|$ >2 $|I_{\rm D}|R_{\rm DS(on)max}$

parameter: $T_{\rm j}$



8 Typ. forward transconductance

 g_{fs} =f(I_D); T_j =25 °C





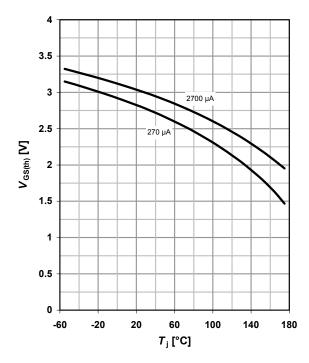
9 Drain-source on-state resistance

 $R_{DS(on)}$ =f(T_{j}); I_{D} =100 A; V_{GS} =10 V

10 Typ. gate threshold voltage

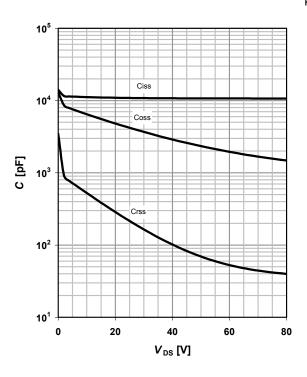
 $V_{GS(th)}$ = $f(T_j)$; V_{GS} = V_{DS}

parameter: I_D



11 Typ. capacitances

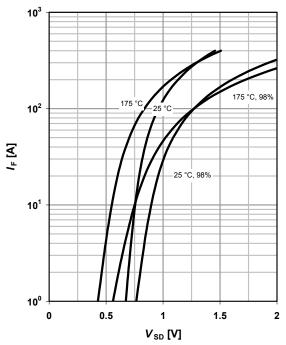
 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$



12 Forward characteristics of reverse diode

$$I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$$

parameter: $T_{\rm j}$





13 Avalanche characteristics

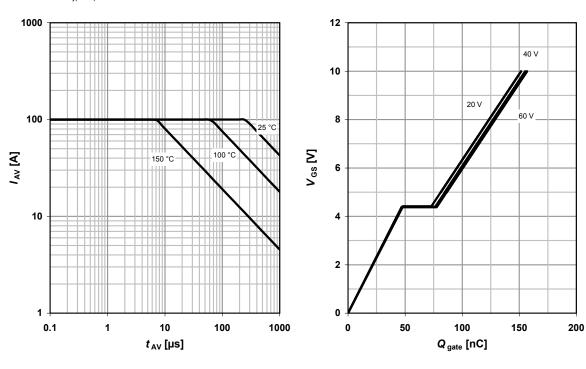
 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

parameter: $T_{j(start)}$

14 Typ. gate charge

 $V_{\rm GS}$ =f(Q _{gate}); $I_{\rm D}$ =50 A pulsed

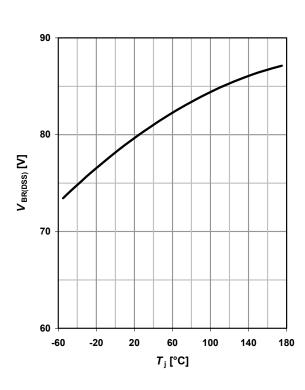
parameter: $V_{\rm DD}$

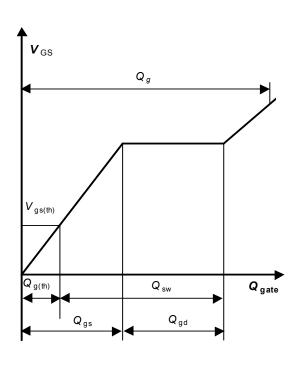


15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_i); I_D=1 \text{ mA}$

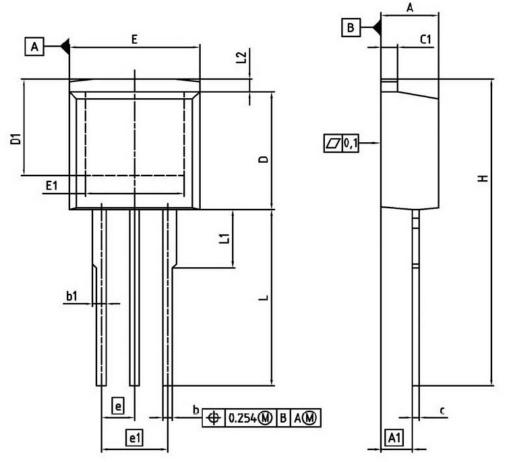
16 Gate charge waveforms



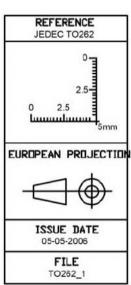




PG-TO262-3 (I²-Pak)

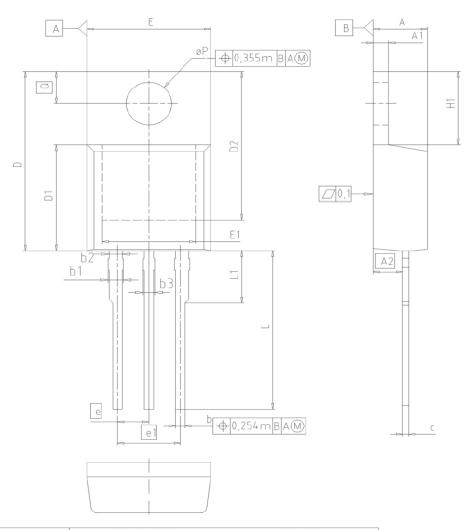


DIM	MILLIM	IETERS	INC	HES
MIU	MIN	MAX	MIN	MAX
Α	4.300	4.572	0.169	0.180
A1	2.150	2.718	0.085	0.107
b	0.650	0.864	0.026	0.034
lo1	0.635	1.400	0.025	0.055
С	0.330	0.600	0.013	0.024
c1	1.170	1.400	0.046	0.055
D	8.509	9.450	0.335	0.372
D1	6.900		0.272	-
E	9.700	10.363	0.382	0.408
E1	6.500	8.600	0.256	0.339
6	2.5	40	0.1	100
e1	5.0	5.080		200
N	3			3
L	13.000	14.000	0.512	0.551
L1		4.800		0.189
L2	-	1.727		0.068

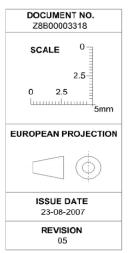




PG-TO220-3



DIM	MILLIN	METERS	INCHES		
DIIVI	MIN	MAX	MIN	MAX	
Α	4.30	4.57	0.169	0.180	
A1	1.17	1.40	0.046	0.055	
A2	2.15	2.72	0.085	0.107	
b	0.65	0.86	0.026	0.034	
b1	0.95	1.40	0.037	0.055	
b2	0.95	1.15	0.037	0.045	
b3	0.65	1.15	0.026	0.045	
С	0.33	0.60	0.013	0.024	
D	14.81	15.95	0.583	0.628	
D1	8.51	9.45	0.335	0.372	
D2	12.19	13.10	0.480	0.516	
E	9.70	10.36	0.382	0.408	
E1	6.50	8.60	0.256	0.339	
е	2.	54	0.100		
e1	5.08		0.200		
N		3	3		
H1	5.90	6.90	0.232	0.272	
L	13.00	14.00	0.512	0.551	
L1	-	4.80	-	0.189	
øΡ	3.60	3.89	0.142	0.153	
Q	2.60	3.00	0.102	0.118	





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